



**SLOVENSKI STANDARD**  
**SIST EN 61124:2007**  
**01-januar-2007**

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**Preskušanje zanesljivosti – Ustreznostni preskusi za konstantno pogostost odpovedi in konstantno intenzivnost odpovedi (IEC 61124:2006)**

Reliability testing - Compliance tests for constant failure rate and constant failure intensity

Prüfungen der Funktionsfähigkeit - Prüfpläne für konstante Ausfallrate und konstante Ausfalldichte

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Essais de fiabilité - Plans d'essais de conformité d'un taux de défaillance constant et d'une intensité de défaillance constante

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**Ta slovenski standard je istoveten z: EN 61124:2006**

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**ICS:**

19.020	Preskuševalni pogoji in postopki na splošno	Test conditions and procedures in general
21.020	Značilnosti in načrtovanje strojev, aparatov, opreme	Characteristics and design of machines, apparatus, equipment

**SIST EN 61124:2007**

**en**

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EUROPEAN STANDARD  
NORME EUROPÉENNE  
EUROPÄISCHE NORM

**EN 61124**

June 2006

ICS 03.120.30; 19.020; 21.020

English version

**Reliability testing -  
Compliance tests for constant failure rate  
and constant failure intensity  
(IEC 61124:2006)**

Essais de fiabilité -  
Plans d'essais de conformité d'un taux de  
défaillance constant et d'une intensité de  
défaillance constante  
(CEI 61124:2006)

Prüfungen der Funktionsfähigkeit -  
Prüfpläne für konstante Ausfallrate  
und konstante Ausfalldichte  
(IEC 61124:2006)

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Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**Central Secretariat: rue de Stassart 35, B - 1050 Brussels**

## Foreword

The text of document 56/1081/FDIS, future edition 2 of IEC 61124, prepared by IEC TC 56, Dependability, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61124 on 2006-05-01.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2007-02-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2009-05-01

Annex ZA has been added by CENELEC.

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## Endorsement notice

The text of the International Standard IEC 61124:2006 was approved by CENELEC as a European Standard without any modification.

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## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-191	- <sup>1)</sup>	International Electrotechnical Vocabulary (IEV) Chapter 191: Dependability and quality of service	-	-
IEC 60300-3-5	2001	Dependability management Part 3-5: Application guide - Reliability test conditions and statistical test principles	-	-
IEC 60605-2	- <sup>1)</sup>	Equipment reliability testing Part 2: Design of test cycles	-	-
IEC 60605-3	Series	Equipment reliability testing Part 3: Preferred test conditions	-	-
IEC 60605-4	2001	Equipment reliability testing Part 4: Statistical procedures for exponential distribution - Point estimates, confidence intervals, prediction intervals and tolerance intervals	-	-
IEC 60605-6	- <sup>1)</sup>	Equipment reliability testing Part 6: Tests for the validity of the constant failure rate or constant failure intensity assumptions	-	-
IEC 61123	1991	Reliability testing - Compliance test plans for success ration	-	-

<sup>1)</sup> Undated reference.

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INTERNATIONALE  
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STANDARD

CEI  
IEC

61124

Deuxième édition  
Second edition  
2006-03

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Международная Электротехническая Комиссия

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For price, see current catalogue*

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

**RELIABILITY TESTING –  
COMPLIANCE TESTS FOR CONSTANT FAILURE RATE  
AND CONSTANT FAILURE INTENSITY**

## FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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International Standard IEC 61124 has been prepared by IEC technical committee 56: Dependability.

This second edition of IEC 61124 cancels and replaces the first edition published in 1997 and constitutes a technical revision.

The main changes with respect to the previous edition are as follows:

A number of new test plans have been added based on the Russian standard GOST 27.402 and it is intended to align the new edition of MIL-HDBK-781 with this edition. Algorithms for optimizing test plans using a spreadsheet program are given and a number of optimized test plans are listed. Furthermore, emphasis is laid on the fact that the test should be repeated following design changes.

Discrepancies in test plans A, B as well as Annexes A and B that originated in IEC 60605-7 have been corrected so these test plans differ from those given in the first edition of IEC 61124. As requested by the national committees, mathematical background material and spreadsheet program information have been moved to informative annexes. In addition, the symbol lists have been divided, so that some annexes have separate lists of symbols.

Guidance on how to choose test plans has been added as well as guidance on how to use spreadsheet programs to create them. Test plans A.1 to A.9 and B.1 to B.13 have been corrected.

Subclauses 8.1, 8.2, 8.3, Clause 9, Annex C, Clauses G.2, I.2, I.3 and Annex J are unchanged, except for updated terminology and references.

The text of this standard is based on the following documents:

FDIS	Report on voting
56/1081/FDIS	56/1095/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

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